

Review of Performance: (VEE 235/P2 Digital 2, Fall 2016, 10 students)
 Submitted by: Nelchor Permitez Ed. D.

Institutional Student Learning Outcomes (ISLO):

- ILO1: Effective oral communication
- ILO2: Effective written communication
- ILO3: Critical thinking
- ILO4: Problem Solving
- ILO5: Intercultural knowledge and competence
- ILO6: Information literacy
- ILO7: Foundation and skills for life long learning
- ILO8: Quantitative reasoning

Program Student Learning Outcomes (PSLO)

- PLO1: Practice Safety and occupational health procedures in the workplace.
- PLO2: Use electronic tools and test equipment competently.
- PLO3: Interpret schematic diagrams and waveforms.
- PLO4: Build electronic projects to a given specification.
- PLO5: Practice a career in the Telecomm Industry.
- PLO6: Troubleshoot microwave, fiber optics and telephone system.

SLO#	Program SLO#	I, D, M	ISLO	Reflection/Comment
1. Demonstrate knowledge in the operations of register, memory, and microprocessor circuits.	Interpret schematics diagrams and waveforms.	D	7	10 students (9 males; 1 female) out of 10 students (100%) successfully completed this CSLO as measured by using hands on experiments and a written quiz.
2. Show understanding in digital arithmetic counting circuits.	Interpret schematics diagrams and	D	7	10 students (9 males; 1 female) out of 10 students (100%) successfully completed this CSLO as measured by using hands on experiments and a written quiz.

	waveforms.			
3. Exhibit knowledge in data conversion, selector and distributor circuits.	Interpret schematics diagrams and waveforms.	M	7	10 students (9 males; 1 female) out of 10 students (100%) successfully completed this CSLO as measured by using hands on experiments and a written quiz.

Additional observations: Needs more NIDA cards for digital set to accommodate growing number of students in electronics and telecommunication program..

Special comments: 10 students (100%) got a grade of “C” and higher.

Recommendations: Time to purchase new 4 sets of NIDA trainer console, logic probes and test probes of DVM to replace the worn out devices and instruments.

Submitted by:

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